

Notice of References Cited	Application/Control No. 10/699,142	Applicant(s)/Patent Under Reexamination PARK ET AL.	
	Examiner Jeff Piziali	Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0030768 A1	03-2002	Wu, I-Wei	349/42
*	B	US-7,158,129 B2	01-2007	Nakajima, Mutsumi	345/207
*	C	US-7,034,309 B2	04-2006	Mochizuki, Chiori	250/370.09
*	D	US-7,009,663 B2	03-2006	Abileah et al.	349/12
*	E	US-6,947,102 B2	09-2005	den Boer et al.	349/12
*	E	US-6,243,069 B1	06-2001	Ogawa et al.	345/102
*	G	US-6,184,946 B1	02-2001	Ando et al.	349/42
*	H	US-5,838,308 A	11-1998	Knapp et al.	345/173
*	I	US-5,485,177 A	01-1996	Shannon et al.	345/182
*	J	US-5,386,543 A	01-1995	Bird, Neil C.	358/1.1
*	K	US-5,204,661 A	04-1993	Hack et al.	345/88
*	L	US-5,168,382 A	12-1992	Tsujikawa, Susumu	349/17
*	M	US-5,051,570 A	09-1991	Tsujikawa et al.	250/201.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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